

Recent activities (2005-2011) in Electronics testing in the UK

The codes provided below are the EPSRC UK funded projects. Detailed information can be found on EPSRC web site:

<http://gow.epsrc.ac.uk>

Universities

Southampton University, UK

Bashir Al-Hashimi

General Chair and local organiser of ETS'06

General Chair of DATE'11

Mark Zwolinski

Saqib Khursheed

EP/H014608/1 Configurable Analogue Transistors: Conquering Unreliability in a Shrinking World

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/H014608/1>

EP/H011420/1 Variation-Aware Test for NanoScale CMOS Integrated Circuits

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/H011420/1>

EP/G067740/1 Next Generation Energy-Harvesting Electronics - holistic approach

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/G067740/1>

EP/E035965/1 Electronics Design

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E035965/1>

EP/E002064/1 Meeting the design challenges of the nano-CMOS electronics

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E002064/1>

EP/D057663/1 Reliable Low Power Embedded Computing Systems (ROPEUST)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/D057663/1>

GR/S05557/01 Low-Power Built-in-Self-Test (LOBIST)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=GR/S05557/01>

Newcastle University, UK

Gordon Russell

Alex Yakovlev

General Chair and local organiser of ASYNC'08

PC Chair ASYNC'06

DATE'06 Workshop "Future Interconnects and Networks on Chip"

Alex Bystrov

Chair of tutorials at ASYNC'08

Chair of IEEE International Workshop on Impact of Low-Power design on Test and Reliability –

LPonTR 2008-2011

ETTTC contact for UK

EP/I005900/1 VARMA - Variability Modelling and Analysis Tool

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/I005900/1>
EP/G066361/1 Reliable cell design methods for variable processes (RelCel)
<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/G066361/1>
EP/G066728/1 Next Generation Energy-Harvesting Electronics - holistic approach
<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/G066728/1>
EP/C512812/1 Next Generation Of Interconnection Technology For Multiprocessor SoC
<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=EP/C512812/1>
EP/D068843/1 EDA tools for strained Si CMOS cell libraries with variability models
<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/D068843/1>
EP/C007298/1 Synchronizer Reliability in the Next Generation of SoC with Multiple Clocks
<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=EP/C007298/1>
GR/S12036/01 Synthesis and TEsting of Low-Latency Asynchronous circuits (STELLA)
<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=GR/S12036/01>
EU project ATHIS on testing of high-temperature electronics

Lancaster University

Andrew Richardson

Workshop on Reliability & DfX Engineering for System-in-Package Technologies (SiPeX) fringe to ETS'08

EP/H03014X/1 An Innovative Electronics Manufacturing Research Centre

<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=EP/H03014X/1>

GR/S40626/01 Advanced Cosserat Analysis for Diagnostic Evaluation in Microsystems Engineering

<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=GR/S40626/01>

University of Glasgow, UK

Asen Asenov

Scott Roy

EP/G04130X/1 ENIAC MOdeling and DEsign of Reliable, process variation-aware Nanoelectronic devices, circuits and systems (MODERN)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/G04130X/1>

EP/E003125/1 Meeting the design challenges of the nano-CMOS electronics

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E003125/1>

EP/E038344/1 Atomic Scale Simulation of Nanoelectronic Devices

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E038344/1>

GR/R47325/01 Understanding and Utilising Fluctuations in Systems of Deep Sub-Micron MOS Devices

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=GR/R47325/01>

Bristol University, UK

Dhiraj Pradhan,

Costas Argyrides

EP/G032904/1 Process Variation Aware Synthesis of Nano-CMOS Circuits

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/G032904/1>

GR/S40855/01 Logic Verification, Synthesis and Test in a New Unified Framework and Low Power Testable Designs

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=GR/S40855/01>

Edinburgh University, UK

Aristides Efthymiou

EP/C547861/1 Automatic Test Pattern Generation and Scan Insertion for Asynchronous Circuits
<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/C547861/1>

Representatives of companies frequently participating in public symposia

Pete Harrod, ARM Limited (UK)
Shidhartha Das, ARM Limited (UK)
David Flynn, ARM Limited (UK)
Michael O'Sullivan, Cadence, UK
E.Cormack - DfT Solutions (UK)
Patrick Au, IBM (UK)

Related research - Dependability

Cliff Jones, Newcastle University, UK
Alexander Romanovsky, Newcastle University, UK

Newcastle:

EP/E035329/1 Trustworthy Ambient Systems (TRAMS)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E035329/1>

GR/N13999/01 INTERDISCIPLINARY RESEARCH COLLABORATION IN DEPENDABILITY OF COMPUTER-BASED SYSTEMS

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=GR/N13999/01>

Bev Littlewood , City University, UK

EP/E000517/1 Interdisciplinary Design and Evaluation of Dependability (INDEED 1)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E000517/1>

Ian Sommerville , Lancaster University, UK

EP/E000320/1 Interdisciplinary Design and Evaluation of Dependability (INDEED 2)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E000320/1>

Stuart Anderson, University of Edinburgh, UK

EP/E001297/1 Interdisciplinary Design and Evaluation of Dependability (INDEED 3)

<http://gow.epsrc.ac.uk/ViewGrant.aspx?GrantRef=EP/E001297/1>

Alan Burns , University of York, UK

EP/E001580/1 Interdisciplinary Design and Evaluation of Dependability (INDEED 4)

<http://gow.epsrc.ac.uk/NGBOViewGrant.aspx?GrantRef=EP/E001580/1>